


<b>Search Notes</b> 	<b>Application/Control No.</b> 10567757	<b>Applicant(s)/Patent Under Reexamination</b> OHNO ET AL.
	<b>Examiner</b> Jafar Parsa	<b>Art Unit</b> 1621

SEARCHED			
Class	Subclass	Date	Examiner
570	165, 177, 178	8/17/08	jp

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	8/17/08	jp
inventor name search	8/17/08	jp

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
570	165, 177, 178	8/17/2008	JP

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